

SIPMOS® Small-Signal-Transistor

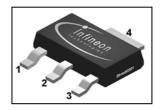
Features

- P-Channel
- Enhancement mode
- Logic level
- Avalanche rated
- dv/dt rated
- Pb-free lead plating; RoHS compliant

Product Summary

V_{DS}	-60	V
$R_{\mathrm{DS(on),max}}$	0.3	Ω
I _D	-1.9	Α

PG-SOT-223



Туре	Package	Tape and Reel Information	Marking
BSP 171 P	PG-SOT-223	L6327: 1000 pcs/reel	171P



Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
			steady state	
Continuous drain current	I _D	T _A =25 °C ¹⁾	-1.9	А
		T _A =70 °C ¹⁾	-1.5	
Pulsed drain current	I _{D,pulse}	T _A =25 °C	-7.6	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =-1.9 A, $R_{\rm GS}$ =25 Ω	70	mJ
Reverse diode dv/dt	dv/dt	$I_{\rm D}$ =-1.9 A, $V_{\rm DS}$ =-48 V, di/dt=-200 A/µs, $T_{\rm j,max}$ =150 °C	-6	kV/μs
Gate source voltage	V_{GS}		±20	V
Power dissipation	P _{tot}	T _A =25 °C ¹⁾	1.8	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	





Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - soldering point	R thJS		-	-	25	K/W
Thermal resistance, junction - ambient	$R_{ m thJA}$	minimal footprint, steady state	-	-	110	
		6 cm ² cooling area ¹⁾ , steady state	-	-	70	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =-250 μA	-60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	V _{DS} =V _{GS} , I _D =-460 μA	-1	-1.5	-2	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =-60 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	-0.1	-1	μA
		V _{DS} =-60 V, V _{GS} =0 V, T _j =125 °C	1	-10	-100	
Gate-source leakage current	I _{GSS}	V _{GS} =-20 V, V _{DS} =0 V	-	-10	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =-4.5 V, I _D =-1.5 A	ı	0.3	0.45	Ω
		V _{GS} =-10 V, I _D =-1.9 A	ı	0.21	0.3	
Transconductance	g _{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = -1.5 \text{ A}$	1.4	2.7	-	S

 $^{^{1)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss		-	365	460	pF
Output capacitance	C _{oss}	V _{GS} =0 V, V _{DS} =-25 V, <i>f</i> =1 MHz	-	105	135	
Reverse transfer capacitance	C _{rss}		-	40	55	
Turn-on delay time	t _{d(on)}		-	6	8	ns
Rise time	t _r	V _{DD} =-25 V,	-	25	33	
Turn-off delay time	$t_{\text{d(off)}}$	$V_{\rm GS}$ =-10 V, $I_{\rm D}$ =-1.9 A, $R_{\rm G}$ =6 Ω	-	208	276	
Fall time	t _f		-	87	130	
Gate Charge Characteristics ²⁾	_			ī	ı	
Gate to source charge	Q _{gs}		-	-1.2	-1.6	nC
Gate to drain charge	Q_{gd}	V _{DD} =-48 V, I _D =1.9 A,	-	-5	-7	
Gate charge total	Q _g	V _{GS} =0 to -10 V	1	-13	-20	
Gate plateau voltage	V _{plateau}		ı	-3	-	V
Output charge	Q _{oss}	V _{DD} =-15 V, V _{GS} =0 V	-	-5	-7	
Reverse Diode						
Diode continuous forward current	Is	T -25 °C	-	-	-1.9	Α
Diode pulse current	I _{S,pulse}		-	-	-7.6	
Diode forward voltage	V_{SD}	V _{GS} =0 V, I _F =1.9 A, T _j =25 °C	-	-0.84	-1.1	V
Reverse recovery time	t _{rr}	V_R =-30 V, I_F = $ I_S $, di_F/dt =100 A/ μ s	-	80	120	ns
Reverse recovery charge	Q _{rr}		-	-125	-190	nC

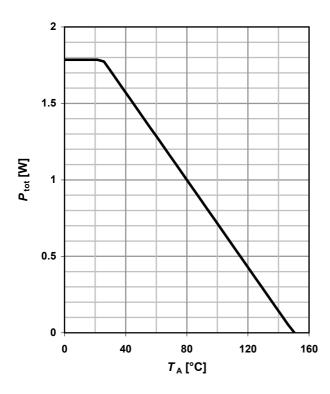
²⁾ See figure 16 for gate charge parameter definition

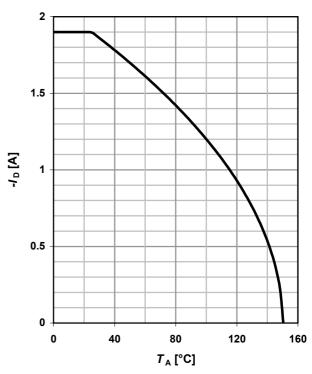


1 Power dissipation

$P_{tot} = f(T_A)$

2 Drain current





3 Safe operating area

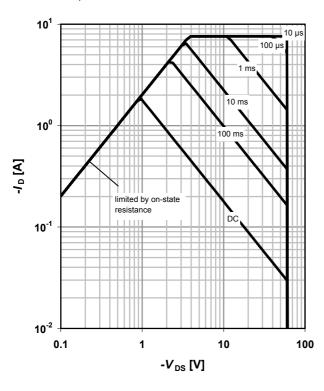
 $I_D = f(V_{DS}); T_A = 25 \text{ °C}^{1)}; D = 0$

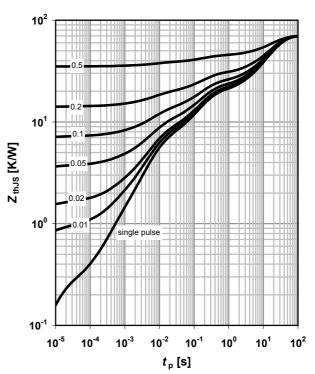
parameter: t_p

4 Max. transient thermal impedance

 Z_{thJA} =f(t_p)

parameter: $D = t_p/T$



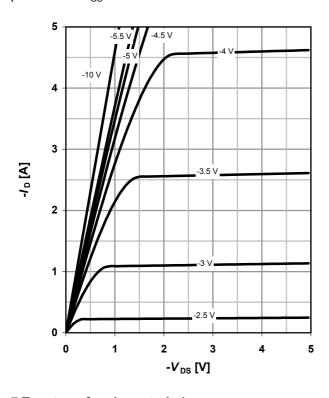




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C$

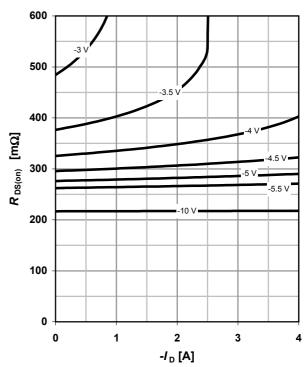
parameter: $V_{\rm GS}$



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

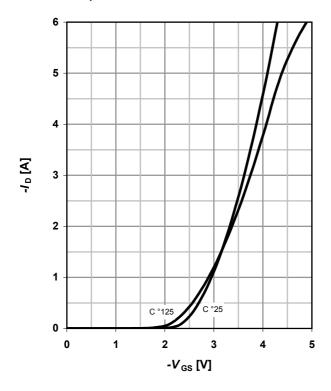
parameter: V_{GS}



7 Typ. transfer characteristics

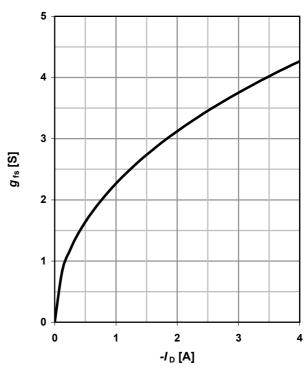
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

parameter: T_i



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C



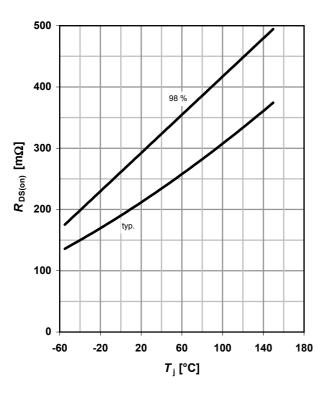


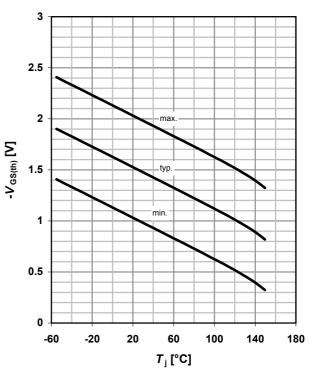
9 Drain-source on-state resistance

$R_{DS(on)} = f(T_j); I_D = -1.9 A; V_{GS} = -10 V$

10 Typ. gate threshold voltage

$$V_{GS(th)}$$
=f(T_j); V_{GS} = V_{DS} ; I_D =-460 μ A





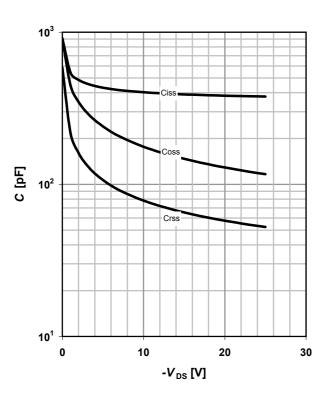
11 Typ. capacitances

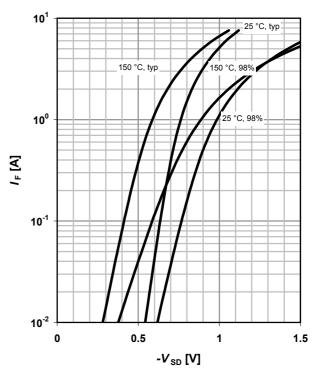
 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$

12 Forward characteristics of reverse diode

 $I_F = f(V_{SD})$

parameter: T_i







13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

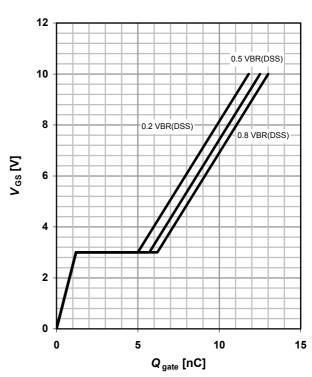
parameter: $T_{j(start)}$

10 C °25 C °25 C °100 C °125 C °125 C °100 C °125 C °100 C

14 Typ. gate charge

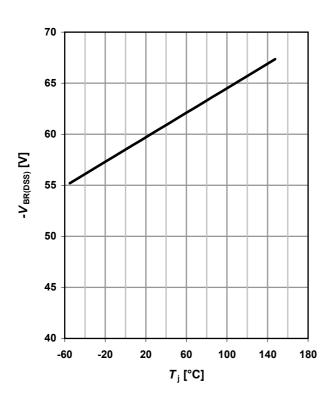
 V_{GS} =f(Q_{gate}); I_{D} =-1.9 A pulsed

parameter: $V_{\rm DD}$

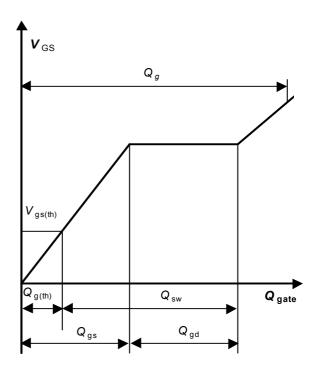


15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=-1 \text{ mA}$



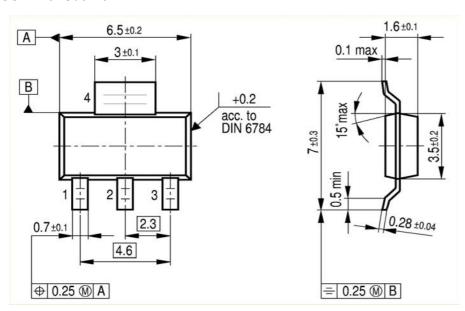
16 Gate charge waveforms



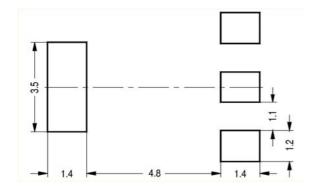


Package Outline

SOT-223: Outline

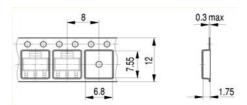


Footprint



Packaging

Tape





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